

2020년 2월 13일(목), 10:45~12:30

Room G (스페이드 II+III, 6층)

**K. Memory (Design & Process Technology) 분과**  
**[TG2-K] Emerging Memory I**

<b>TG2-K-1</b> 10:45~11:15	<b>[초청]</b> <b>TBA</b> 유향근 SK하이닉스
<b>TG2-K-2</b> 11:15~11:45	<b>[초청]</b> <b>Ferroelectric Hf<sub>0.5</sub>Zr<sub>0.5</sub>O<sub>2</sub> Thin Films</b> Si Joon Kim <i>Department of Electrical and Electronics Engineering, Kangwon National University</i>
<b>TG2-K-3</b> 11:45~12:00	<b>Highly Linear and Symmetric Synaptic Function of a Memristive Device for Spiking Neural Network System</b> Jin Joo Ryu <sup>1,2</sup> , Kanghyeok Jeon <sup>1</sup> , Min Kyu Yang <sup>3</sup> , Chunjoong Kim <sup>2</sup> , and Gun Hwan Kim <sup>1</sup> <i><sup>1</sup>Division of Advanced Materials, KRICT, <sup>2</sup>Department of Materials Science and Engineering, Chungnam National University, <sup>3</sup>Division of IT Convergence Engineering, Sahmyook University</i>
<b>TG2-K-4</b> 12:00~12:15	<b>The Origin of Incremental Step Pulse Programming (ISPP) Slope Degradation in NAND Flash Memory</b> Kihoon Nam, Chanyang Park, Jun-Sik Yoon, Hyun-Dong Jang, and Rock-Hyun Ba <sup>†</sup> <i>Department of Electrical Engineering, POSTECH</i>
<b>TG2-K-5</b> 12:15~12:30	<b>Effect of Interface Roughness on Program/Erase Efficiency for 3D Vertical NAND Flash Memory Applications</b> Yongjin Cho, Hyeongwan Oh, Gilsang Yoon, Jaeseok Jin, Donghyun Go, Jounghun Park, and Jeongsoo Lee <i>Department of Electrical Engineering, POSTECH</i>